

Search Notes**Application/Control No.**

10/574,698

Examiner

THANH LAM

**Applicant(s)/Patent under
Reexamination**

OSAWA ET AL.

Art Unit

2834

SEARCHED

Class	Subclass	Date	Examiner
310	179,184, 233-234, 196.	11/23/2008	TL

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
interference searched		11/23/2008	TL

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR